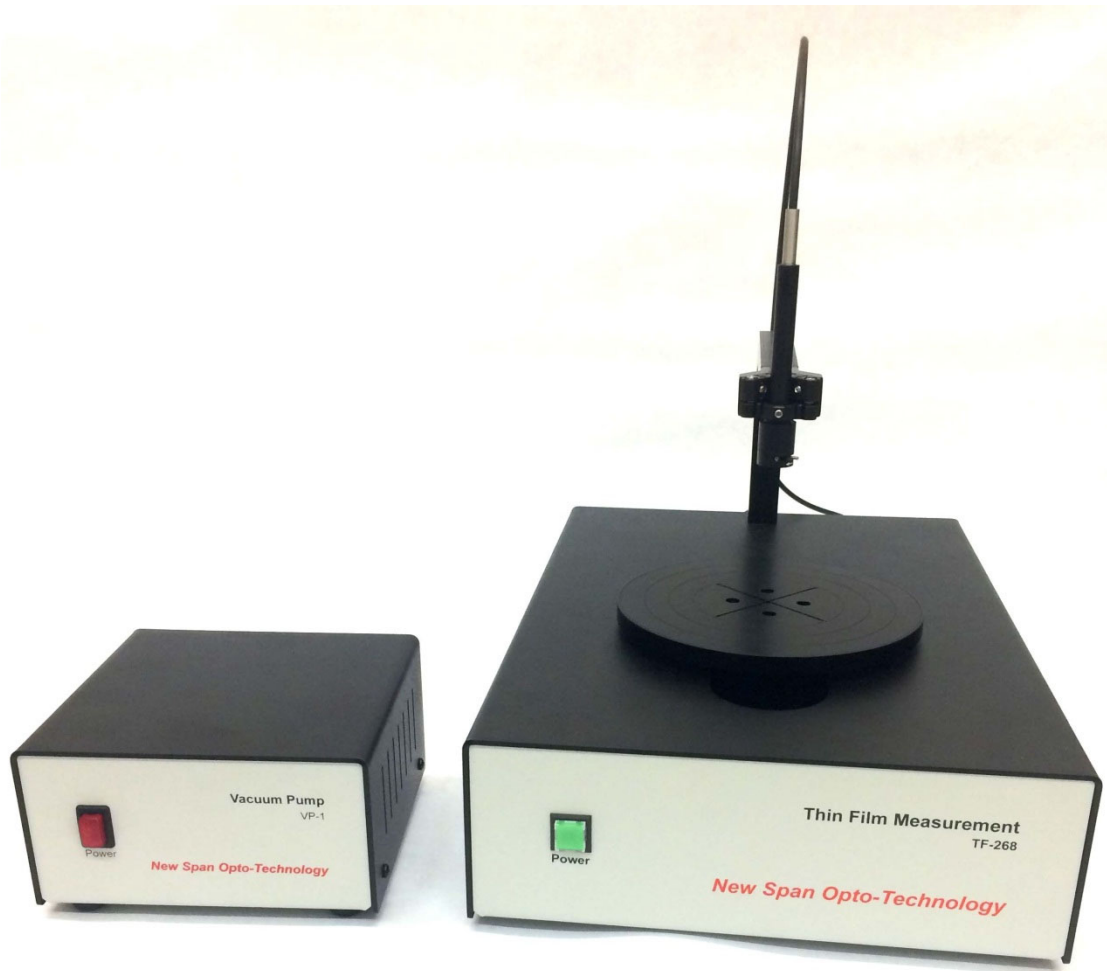


Thin film measurement system



Measure optically the thickness of thin film such as photoresist and dielectrics thinner than 15 micron

